

August 1997

CMOS Analog Multiplexers

Features

- Low Power Consumption
- TTL and CMOS-Compatible Address and Enable Inputs
- 44V Maximum Power Supply Rating
- High Latch-Up Immunity
- Break-Before-Make Switching
- Alternate Source

Applications

- Data Acquisition Systems
- Communication Systems
- Signal Multiplexing/Demultiplexing
- Audio Signal Multiplexing

Description

The DG506A, DG507A, DG508A and DG509A are CMOS Monolithic 16-Channel/Dual 8-Channel and 8-Channel/Dual 4-Channel Analog Multiplexers, which can also be used as demultiplexers. An enable input is provided. When the enable input is high, a channel is selected by the address inputs, and when low, all channels are off.

A channel in the ON state conducts current equally well in both directions. In the OFF state each channel blocks voltages up to the supply rails. The address inputs and the enable input are TTL and CMOS compatible over the full specified operating temperature range.

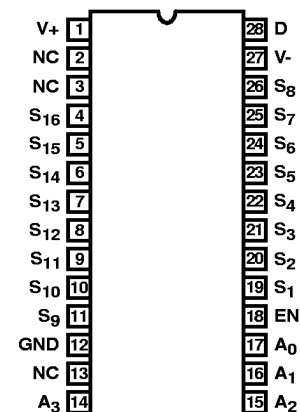
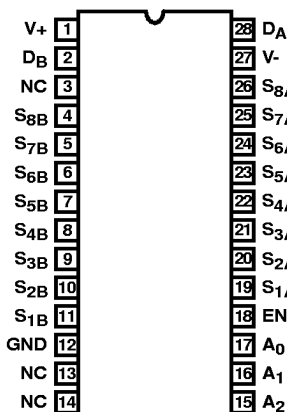
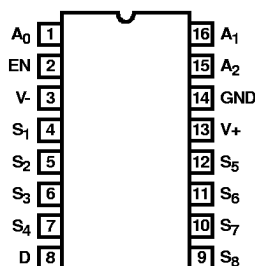
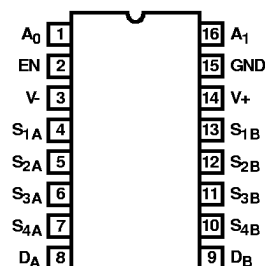
The DG506A, DG507A, DG508A and DG509A are pinout compatible with the industry standard devices.

Ordering Information

PART NUMBER	TEMP. RANGE (°C)	PACKAGE	PKG. NO.
DG506AAK	-55 to 125	28 Ld CERDIP	F28.6
DG506AAK/883B	-55 to 125	28 Ld CERDIP	F28.6
DG506ABK	-25 to 85	28 Ld CERDIP	F28.6
DG506ABY	-25 to 85	28 Ld PDIP	E28.6
DG506ACJ	0 to 70	28 Ld PDIP	E28.6
DG506ACY	0 to 70	28 Ld SOIC	M28.3
DG507AAK	-55 to 125	28 Ld CERDIP	F28.6
DG507AAK/883B	-55 to 125	28 Ld CERDIP	F28.6
DG507ABK	-25 to 85	28 Ld CERDIP	F28.6
DG507ABY	-25 to 85	28 Ld PDIP	E28.6
DG507ACJ	0 to 70	28 Ld PDIP	E28.6
DG507ACK	0 to 70	28 Ld CERDIP	F28.6
DG507ACY	0 to 70	28 Ld SOIC	M28.3
DG508AAK	-55 to 125	16 Ld CERDIP	F16.3

PART NUMBER	TEMP. RANGE (°C)	PACKAGE	PKG. NO.
DG508AAK/883B	-55 to 125	16 Ld CERDIP	F16.3
DG508ABK	-25 to 85	16 Ld CERDIP	F16.3
DG508ABY	-25 to 85	16 Ld SOIC	M16.3
DG508ACJ	0 to 70	16 Ld PDIP	E16.3
DG508ACK	0 to 70	16 Ld CERDIP	F16.3
DG508ACY	0 to 70	16 Ld SOIC	M16.3
DG509AAK	-55 to 125	16 Ld CERDIP	F16.3
DG509AAK/883B	-55 to 125	16 Ld CERDIP	F16.3
DG509ABK	-25 to 85	16 Ld CERDIP	F16.3
DG509ABY	-25 to 85	16 Ld SOIC	M16.3
DG509ACJ	0 to 70	16 Ld PDIP	E16.3
DG509ACK	0 to 70	16 Ld CERDIP	F16.3
DG509ACY	0 to 70	16 Ld SOIC	M16.3

Pinouts

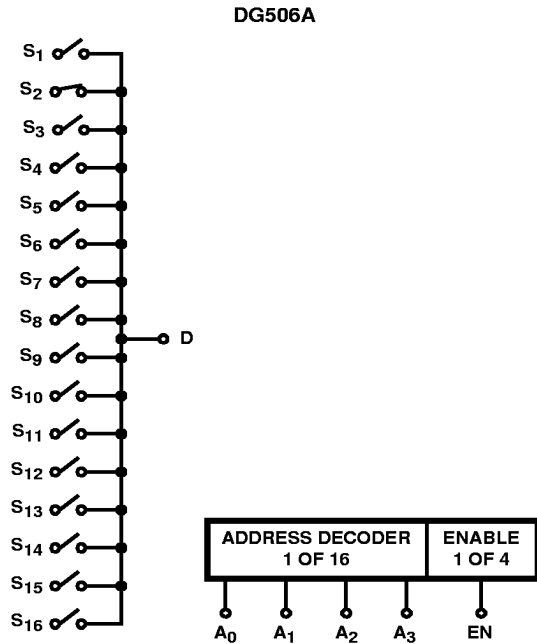
 DG506A (PDIP, CERDIP, SOIC)
TOP VIEW

 DG507A (PDIP, CERDIP, SOIC)
TOP VIEW

 DG508A (PDIP, CERDIP, SOIC)
TOP VIEW

 DG509A (PDIP, CERDIP, SOIC)
TOP VIEW


CAUTION: These devices are sensitive to electrostatic discharge. Users should follow proper IC Handling Procedures.

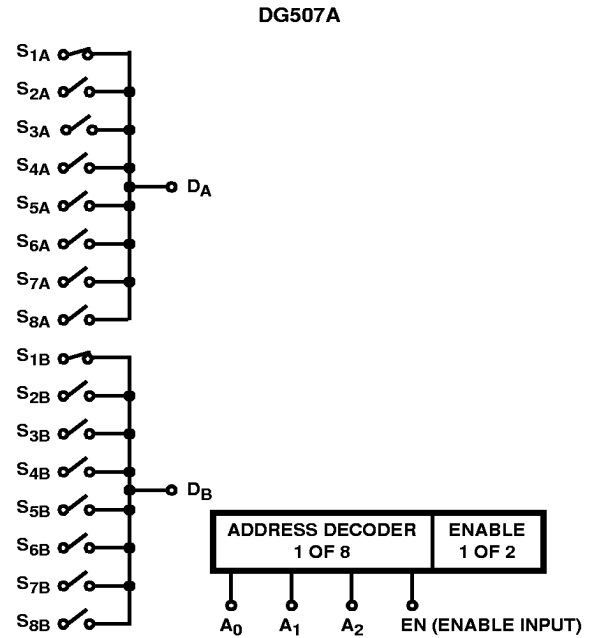
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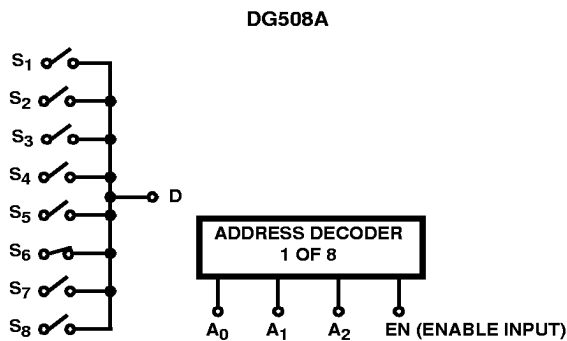
Functional Block Diagrams



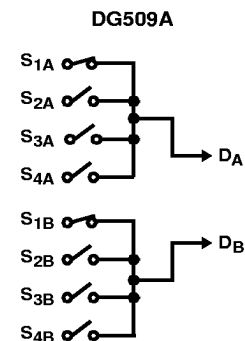
4 Line Binary Address Inputs
(0 0 0 1) and EN = 5V
Above example shows channel 2 turned ON.



3 Line Binary Address Inputs
(0 0 0) and EN = 5V
Above example shows channels 1A and 1B turned ON.

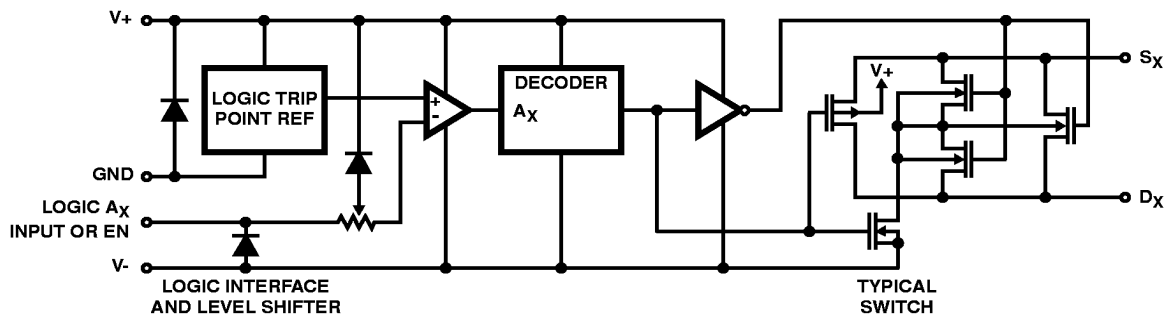


3 Line Binary Address Inputs
(1 0 1) and EN = 1
Above example shows channel 6 turned ON.



2 Line Binary Address Inputs
(0 0) and EN = 1
Above example shows channels 1A and 1B turned ON.

Schematic Diagram



DG506A, DG507A, DG508A, DG509A

Absolute Maximum Ratings

V ₊ to V ₋	44V
V ₋ to Ground	-25V
V _{IN} to Ground (Note 1)	(V ₋ -2V), (V ₊ +2V)
V _S or V _D to V ₊ (Note 1)	+2, (V ₋ -2V)
V _S or V _D to V ₋ (Note 1)	-2, (V ₊ +2V)
Current, any Terminal Except S or D	30mA
Continuous Current, S or D	20mA
Peak Current, S or D (Pulsed at 1ms, 10% Duty Cycle Max)	40mA

Operating Conditions

Operating Temperature Range

C Suffix	0°C to 70°C
B Suffix	-25°C to 85°C
A Suffix	-55°C to 125°C

Thermal Information

Thermal Resistance (Typical, Note 2)	θ_{JA} (°C/W)	θ_{JC} (°C/W)
16 Ld CERDIP Package	75	20
28 Ld CERDIP Package	55	18
16 Ld PDIP Package	100	N/A
28 Ld PDIP Package	60	N/A
16 Ld SOIC Package	100	N/A
28 Ld SOIC Package	70	N/A
Maximum Junction Temperature		
CERDIP Package	175°C	
PDIP Package	150°C	
Maximum Storage Temperature		
C Suffix	-65°C to 125°C	
A and B Suffix	-65°C to 150°C	
Maximum Lead Temperature (Soldering 10s)	300°C	
(SOIC - Lead Tips Only)		

CAUTION: Stresses above those listed in "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress only rating and operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied.

NOTES:

1. Signals on V_S, V_D or V_{IN} exceeding V₊ or V₋ will be clamped by internal diodes. Limit diode forward current to maximum current ratings.
2. θ_{JA} is measured with the component mounted on an evaluation PC board in free air.

Electrical Specifications $T_A = 25^\circ\text{C}$, V₊ = +15V, V₋ = -15V, GND = 0V, V_{EN} = 2.4V, Unless Otherwise Specified

PARAMETER	TEST CONDITIONS	DG506AA, DG507AA, DG508AA, DG509AA			DG506AB/C, DG507AB/C, DG508AB/C, DG509AB/C			UNITS
		MIN	(NOTE 1) TYP	MAX	MIN	(NOTE 1) TYP	MAX	
DYNAMIC CHARACTERISTICS								
Switching Time of Multiplexer, $t_{\text{TRANSITION}}$	See Figure 3	-	0.6	1	-	0.6	-	μs
Break-Before-Make Interval, t_{OPEN}	See Figure 5	-	0.2	-	-	0.2	-	μs
Enable Turn-On Time, $t_{\text{ON(EN)}}$	See Figure 4	-	1	1.5	-	1	-	μs
Enable Turn-Off Time, $t_{\text{OFF(EN)}}$	See Figure 4	-	0.4	1.0	-	0.4	-	μs
Off Isolation, OIRR	$V_{\text{EN}} = 0\text{V}$, $R_{\text{L}} = 1\text{k}\Omega$, $C_{\text{L}} = 15\text{pF}$, $V_{\text{S}} = 7V_{\text{RMS}}$, $f = 500\text{kHz}$ (Note 3)	-	68	-	-	68	-	dB
Source Off Capacitance, $C_{\text{S(OFF)}}$	$V_{\text{S}} = 0\text{V}$, $V_{\text{EN}} = 0\text{V}$, $f = 140\text{kHz}$							
DG506A, DG507A		-	6	-	-	6	-	pF
DG508A, DG509A		-	5	-	-	5	-	pF
Drain Off Capacitance, $C_{\text{D(OFF)}}$	$V_{\text{D}} = 0\text{V}$, $V_{\text{EN}} = 0\text{V}$, $f = 140\text{kHz}$							
DG506A		-	45	-	-	45	-	pF
DG507A		-	23	-	-	23	-	pF
DG508A		-	25	-	-	25	-	pF
DG509A		-	12	-	-	12	-	pF
Charge Injection, Q	See Figure 6							
DG506A, DG507A		-	6	-	-	6	-	pC
DG508A, DG509A		-	4	-	-	4	-	pC
INPUT								
Address Input Current, I_{AH}	$V_{\text{A}} = 2.4\text{V}$	-10	-0.002	-	-10	-0.002	-	μA
Input Voltage High, I_{AH}	$V_{\text{A}} = 15\text{V}$	-	0.006	10	-	0.006	10	μA

DG506A, DG507A, DG508A, DG509A

Electrical Specifications $T_A = 25^\circ\text{C}$, $V_+ = +15\text{V}$, $V_- = -15\text{V}$, $\text{GND} = 0\text{V}$, $V_{\text{EN}} = 2.4\text{V}$, Unless Otherwise Specified **(Continued)**

PARAMETER	TEST CONDITIONS		DG506AA, DG507AA, DG508AA, DG509AA			DG506AB/C, DG507AB/C, DG508AB/C, DG509AB/C			UNITS
			MIN	(NOTE 1) TYP	MAX	MIN	(NOTE 1) TYP	MAX	
Address Input Current Input Voltage Low, I _{AL}	V _{EN} = 2.4V	V _A = 0V	-10	-0.002	-	-10	-0.002	-	μA
	V _{EN} = 0V		-10	-0.002	-	-10	-0.0002	-	μA
SWITCH									
Analog Signal Range, V _{ANALOG}	(Note 5)		-15	-	+15	-15	-	+15	V
Drain Source On Resistance, r _{DS(ON)}	Sequence Each Switch On V _{AL} = 0.8V V _{AH} = 2.4V	I _S = -200μA, V _D = +10V	-	270	400	-	270	450	Ω
		I _S = -200μA, V _D = -10V	-	230	400	-	230	450	Ω
Greatest Change in Drain Source On Resistance Between Channels, Δr _{DS(ON)}	-10V ≤ V _S ≤ +10V Δr _{DS(ON)} = $\frac{r_{DS(ON)MAX} - r_{DS(ON)MIN}}{r_{DS(ON)AVG}}$		-	6	-	-	6	-	%
Source Off Leakage Current, I _{S(OFF)}	V _{EN} = 0V	V _S = +10V, V _D = -10V	-1	0.002	1	-5	0.002	5	nA
		V _S = -10V, V _D = +10V	-1	-0.005	1	-5	-0.005	5	nA
Drain Off Leakage Current, I _{D(OFF)} DG506A	V _{EN} = 0V								
		V _S = -10V, V _D = +10V	-10	0.02	10	-20	0.02	20	nA
V _S = +10V, V _D = -10V		-10	-0.03	10	-20	-0.03	20	nA	
DG507A		V _S = -10V, V _D = +10V	-5	0.007	5	-10	0.007	10	nA
V _S = +10V, V _D = -10V		-5	-0.015	5	-10	-0.015	10	nA	
DG508A		V _S = -10V, V _D = +10V	-	0.01	10	-	0.01	20	nA
V _S = +10V, V _D = -10V		-10	-0.015	-	-20	-0.015	-	nA	
DG509A		V _S = -10V, V _D = +10V	-	0.005	10	-	0.005	20	nA
V _S = +10V, V _D = -10V	-10	-0.008	-	-20	-0.008	-	nA		
Drain On Leakage Current, I _{D(ON)} DG506A	(Note 4) Sequence Each Switch On V _{AL} = 0.8V V _{AH} = 2.4V								
		V _D = V _{S(ALL)} = +10V	-10	0.03	10	-20	0.03	20	nA
V _D = V _{S(ALL)} = -10V		-10	-0.06	10	-20	-0.06	20	nA	
DG507A		V _D = V _{S(ALL)} = +10V	-5	0.015	5	-10	0.015	10	nA
V _D = V _{S(ALL)} = -10V		-5	-0.03	5	-10	-0.03	10	nA	
DG508A		V _D = V _{S(ALL)} = +10V	-	0.015	10	-	0.015	20	nA
V _D = V _{S(ALL)} = -10V		-10	-0.03	-	-20	-0.03	-	nA	
DG509A		V _D = V _{S(ALL)} = +10V	-	0.007	10	-	0.007	20	nA
V _D = V _{S(ALL)} = -10V	-10	-0.015	-	-20	-0.015	-	nA		
POWER SUPPLY CHARACTERISTICS									
Positive Supply Current, I ₊	V _{EN} = 5.0V, V _A = 0V		-	1.3	2.4	-	1.3	2.4	mA
Negative Supply Current, I ₋	V _{EN} = 5.0V, V _A = 0V		-1.5	-0.7	-	-1.5	-0.7	-	mA
Positive Supply Current, I ₊ Standby	V _{EN} = 0V, V _A = 0V		-	1.3	2.4	-	1.3	2.4	mA
Negative Supply Current, I ₋ Standby	V _{EN} = 0V, V _A = 0V		-1.5	-0.7	-	-1.5	-0.7	-	mA

DG506A, DG507A, DG508A, DG509A

Electrical Specifications T_A = Over Operating Temperature Range, $V_+ = +15V$, $V_- = -15V$, $GND = 0V$, $V_{EN} = 2.4V$,
Unless Otherwise Specified

PARAMETER	TEST CONDITIONS		DG506AA, DG507AA, DG508AA, DG509AA			DG506AB/C, DG507AB/C, DG508AB/C, DG509AB/C			UNITS
			MIN	(NOTE 2) TYP	MAX	MIN	(NOTE 2) TYP	MAX	
INPUT									
Address Input Current, Input Voltage High, I _{AH}	V _A = 2.4V		-30	-	-	-	-	-	μA
	V _A = 15V		-	-	30	-	-	-	μA
Address Input Current Input Voltage Low, I _{AL}	V _{EN} = 2.4V	V _A = 0V	-30	-	-	-	-	-	μA
	V _{EN} = 0V		-30	-	-	-	-	-	μA
SWITCHING CHARACTERISTICS									
Analog Signal Range, V _{ANALOG}	(Note 5)		-15	-	+15	-	-	-	V
Drain Source On Resistance, r _{DS(ON)}	Sequence Each Switch On V _{AL} = 0.8V V _{AH} = 2.4V	I _S = -200μA, V _D = +10V	-	-	500	-	-	-	Ω
		I _S = -200μA, V _D = -10V	-	-	500	-	-	-	Ω
Source Off Leakage Current, I _{S(OFF)}	V _{EN} = 0V	V _S = +10V, V _D = -10V	-	-	50	-	-	-	nA
		V _S = -10V, V _D = +10V	-50	-	-	-	-	-	nA
Drain Off Leakage Current, I _{D(OFF)} DG506A	V _{EN} = 0V	V _S = -10V, V _D = +10V	-	-	300	-	-	-	nA
		V _S = +10V, V _D = -10V	-300	-	-	-	-	-	nA
DG507A		V _S = -10V, V _D = +10V	-	-	200	-	-	-	nA
V _S = +10V, V _D = -10V		-200	-	-	-	-	-	nA	
DG508A		V _S = -10V, V _D = +10V	-	-	200	-	-	-	nA
V _S = +10V, V _D = -10V		-200	-	-	-	-	-	nA	
DG509A		V _S = -10V, V _D = +10V	-	-	100	-	-	-	nA
V _S = +10V, V _D = -10V		-100	-	-	-	-	-	nA	
Drain On Leakage Current, I _{D(ON)} DG506A	(Note 4) Sequence Each Switch On V _{AL} = 0.8V V _{AH} = 2.4V	V _D = V _{S(ALL)} = +10V	-	-	300	-	-	-	nA
		V _D = V _{S(ALL)} = -10V	-300	-	-	-	-	-	nA
DG507A		V _D = V _{S(ALL)} = +10V	-	-	200	-	-	-	nA
V _D = V _{S(ALL)} = -10V		-200	-	-	-	-	-	nA	
DG508A		V _D = V _{S(ALL)} = +10V	-	-	200	-	-	-	nA
V _D = V _{S(ALL)} = -10V		-200	-	-	-	-	-	nA	
DG509A		V _D = V _{S(ALL)} = +10V	-	-	100	-	-	-	nA
V _D = V _{S(ALL)} = -10V		-100	-	-	-	-	-	nA	
POWER SUPPLY CHARACTERISTICS									
Positive Supply Current, I ₊	V _{EN} = 5.0V, V _A = 0V		-3.2	-	4.5	-	-	-	mA
Negative Supplu Current I ₋	V _{EN} = 5.0V, V _A = 0V		-3.2	-	4.5	-	-	-	mA
Positive Standby Supply Current I ₊	V _{EN} = 0V, V _A = 0V		-3.2	-	4.5	-	-	-	mA
Negative Standby Supply Current I ₋	V _{EN} = 0V, V _A = 0V		-3.2	-	4.5	-	-	-	mA

NOTES:

- Typical values are for design aid only, not guaranteed and not subject to production testing.
- The algebraic convention whereby the most negative value is a minimum, and the most positive value is a maximum, is used in this data sheet.
- Off isolation = $20\log |V_S|/|V_D|$, where V_S = input to Off switch, and V_D = output due to V_S .
- $I_{D(ON)}$ is leakage from driver into "ON" switch.
- Parameter not tested. Parameter guaranteed by design or characterization.

Typical Performance Curves

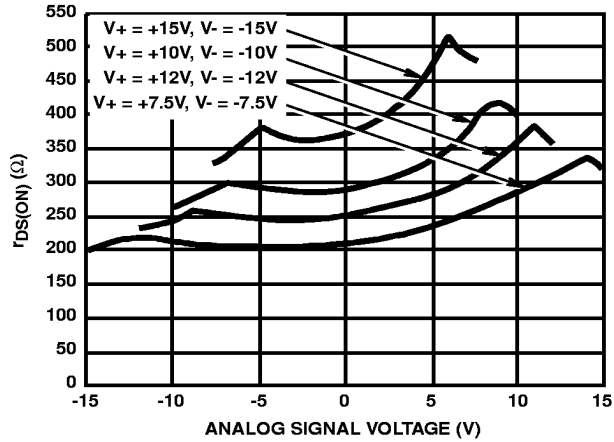


FIGURE 1. $r_{DS(ON)}$ vs ANALOG SIGNAL VOLTAGE vs SUPPLY VOLTAGE

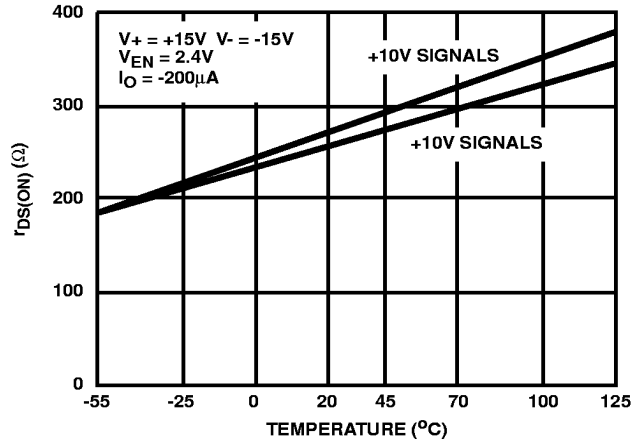
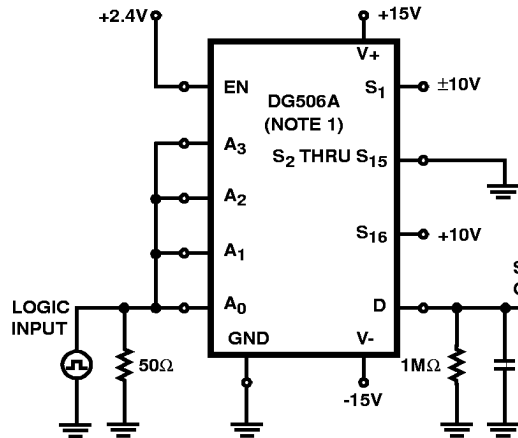


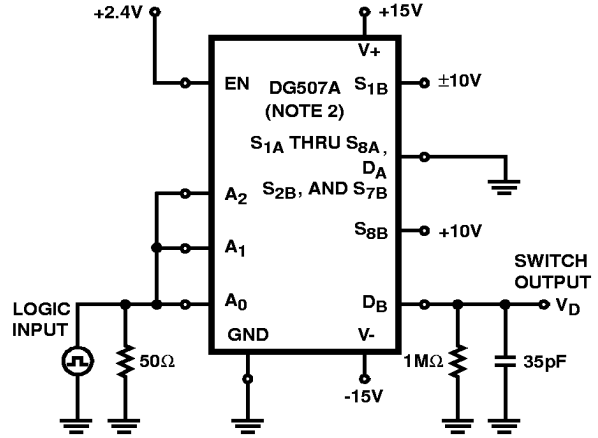
FIGURE 2. TYPICAL $r_{DS(ON)}$ VARIATION WITH TEMPERATURE

Test Circuits and Waveforms



NOTE: 1. Similar connections for DG508A

FIGURE 3A. $t_{TRANSITION}$ SWITCHING TIME TEST CIRCUIT



NOTE: 2. Similar connections for DG509A

FIGURE 3B. $t_{TRANSITION}$ SWITCHING TIME TEST CIRCUIT

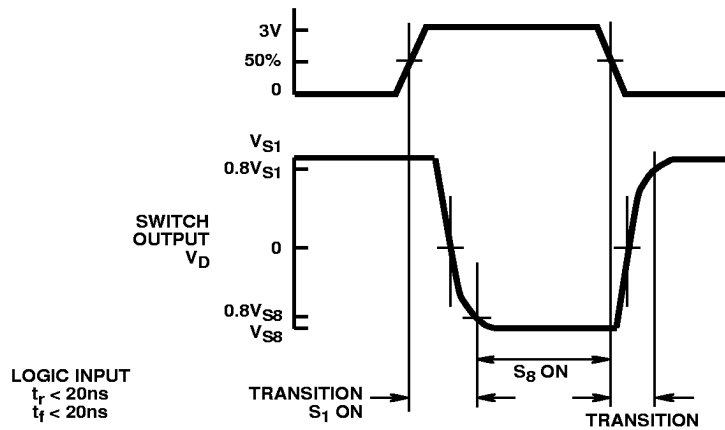
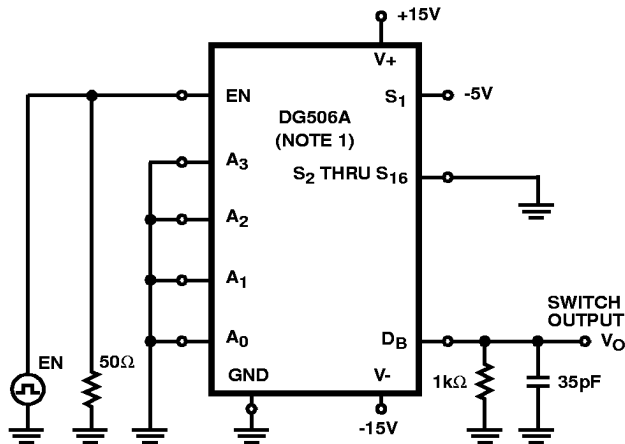


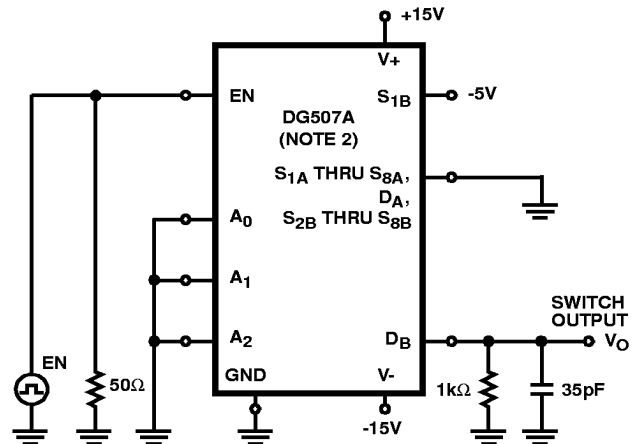
FIGURE 3C. $t_{TRANSITION}$ SWITCHING TIME WAVEFORMS

Test Circuits and Waveforms (Continued)



NOTE: 1. Similar connections for DG508A

FIGURE 4A. ENABLE t_{ON} and t_{OFF} SWITCHING TIME TEST CIRCUIT



NOTE: 2. Similar connections for DG509A

FIGURE 4B. ENABLE t_{ON} and t_{OFF} SWITCHING TIME TEST CIRCUIT

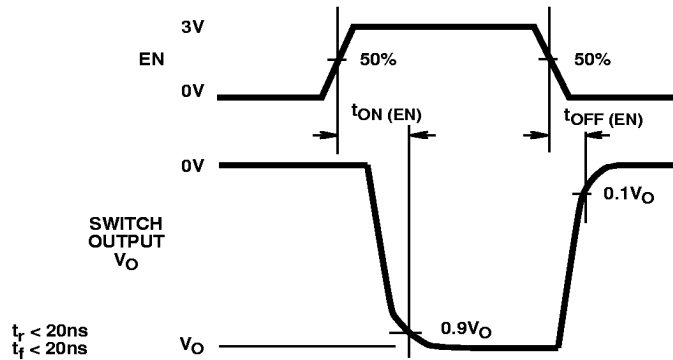
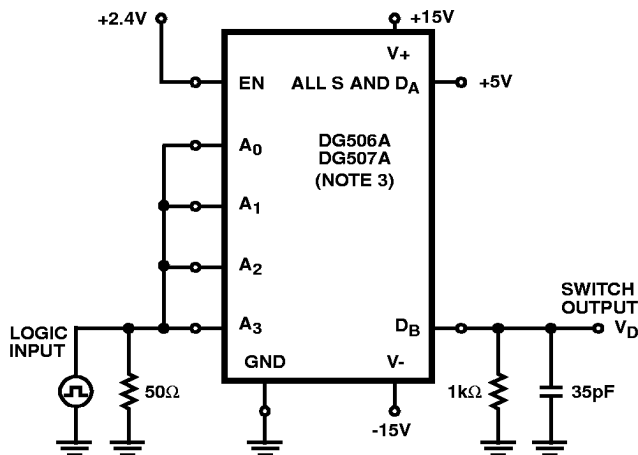


FIGURE 4C. ENABLE t_{ON} and t_{OFF} SWITCHING TIME WAVEFORMS



NOTE: 3. Similar connections for DG508A, DG509A.

FIGURE 5A. t_{OPEN} (BREAK-BEFORE-MAKE) SWITCHING TIME TEST CIRCUIT

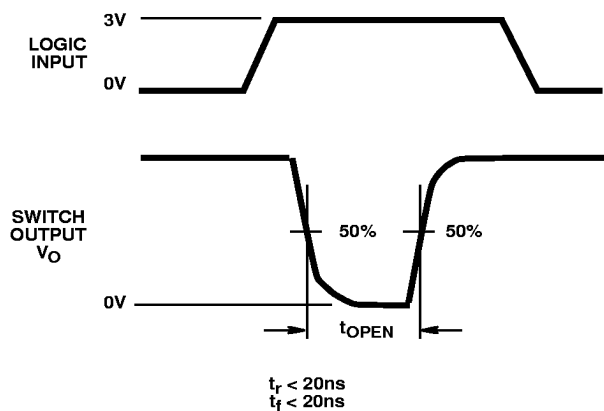
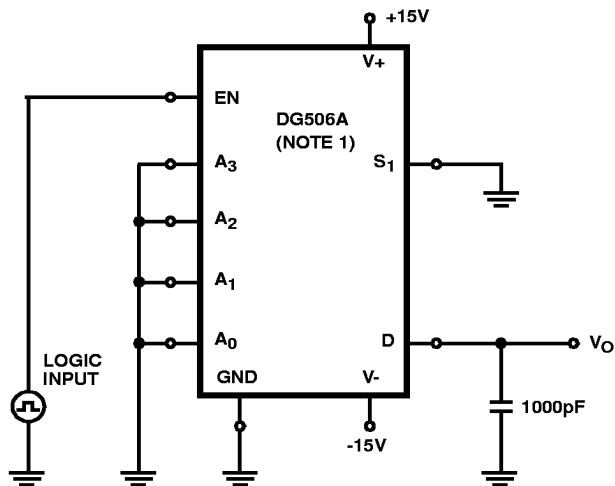


FIGURE 5B. t_{OPEN} (BREAK-BEFORE-MAKE) SWITCHING TIME WAVEFORMS

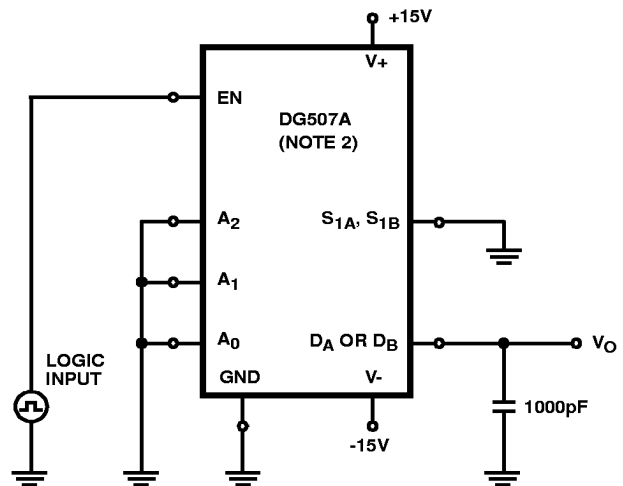
Test Circuits and Waveforms (Continued)



NOTE:

1. Similar connections for DG508A.

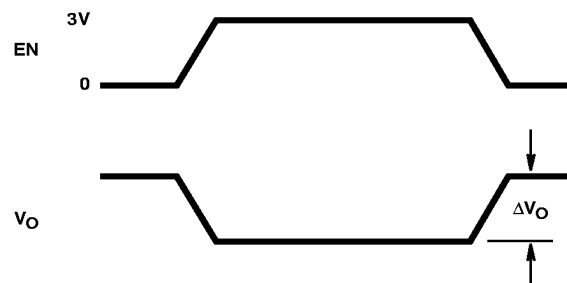
FIGURE 6A. CHARGE INJECTION TEST CIRCUIT



NOTE:

2. Similar connections for DG509A.

FIGURE 6B. CHARGE INJECTION TEST CIRCUIT



ΔV_O is the measured voltage error due to charge injection.
The error voltage in Coulombs is $Q = C_L \times \Delta V_O$.

FIGURE 6C. CHARGE INJECTION WAVEFORMS

Truth Tables

DG506A

A ₃	A ₂	A ₁	A ₀	EN	ON SWITCH
X	X	X	X	0	None
0	0	0	0	1	1
0	0	0	1	1	2
0	0	1	0	1	3
0	0	1	1	1	4
0	1	0	0	1	5
0	1	0	1	1	6
0	1	1	0	1	7
0	1	1	1	1	8
1	0	0	0	1	9
1	0	0	1	1	10
1	0	1	0	1	11
1	0	1	1	1	12
1	1	0	0	1	13
1	1	0	1	1	14
1	1	1	0	1	15
1	1	1	1	1	16

Logic "0" = V_{AL}, V_{ENL} ≤ 0.8V, Logic "1" = V_{AH}, V_{ENH} ≥ 2.4V.

DG508A

A ₂	A ₁	A ₀	EN	ON SWITCH
X	X	X	0	None
0	0	0	1	1
0	0	1	1	2
0	1	0	1	3
0	1	1	1	4
1	0	0	1	5
1	0	1	1	6
1	1	0	1	7
1	1	1	1	8

A₀, A₁, A₂, EN
Logic "1" = V_{AH} ≥ 2.4V, Logic "0" = V_{AL} ≤ 0.8V

DG507A

A ₂	A ₁	A ₀	EN	ON SWITCH
X	X	X	0	None
0	0	0	1	1
0	0	1	1	2
0	1	0	1	3
0	1	1	1	4
1	0	0	1	5
1	0	1	1	6
1	1	0	1	7
1	1	1	1	8

Logic "0" = V_{AL}, V_{ENL} ≤ 0.8V, Logic "1" = V_{AH}, V_{ENH} ≥ 2.4V.

DG509A

A ₁	A ₀	EN	ON SWITCH
X	X	0	None
0	0	1	1A, 1B
0	1	1	2A, 2B
1	0	1	3A, 3B
1	1	1	4A, 4B

A₀, A₁, EN
Logic "1" = V_{AH} ≥ 2.4V, Logic "0" = V_{AL} ≤ 0.8V.

Die Characteristics

DIE DIMENSIONS:

3810 μ m x 2770 μ m

METALLIZATION:

Type: Al

Thickness: 10k $\text{\AA}$ $\pm$ 1k $\text{\AA}$

PASSIVATION:

Type: PSG/Nitride

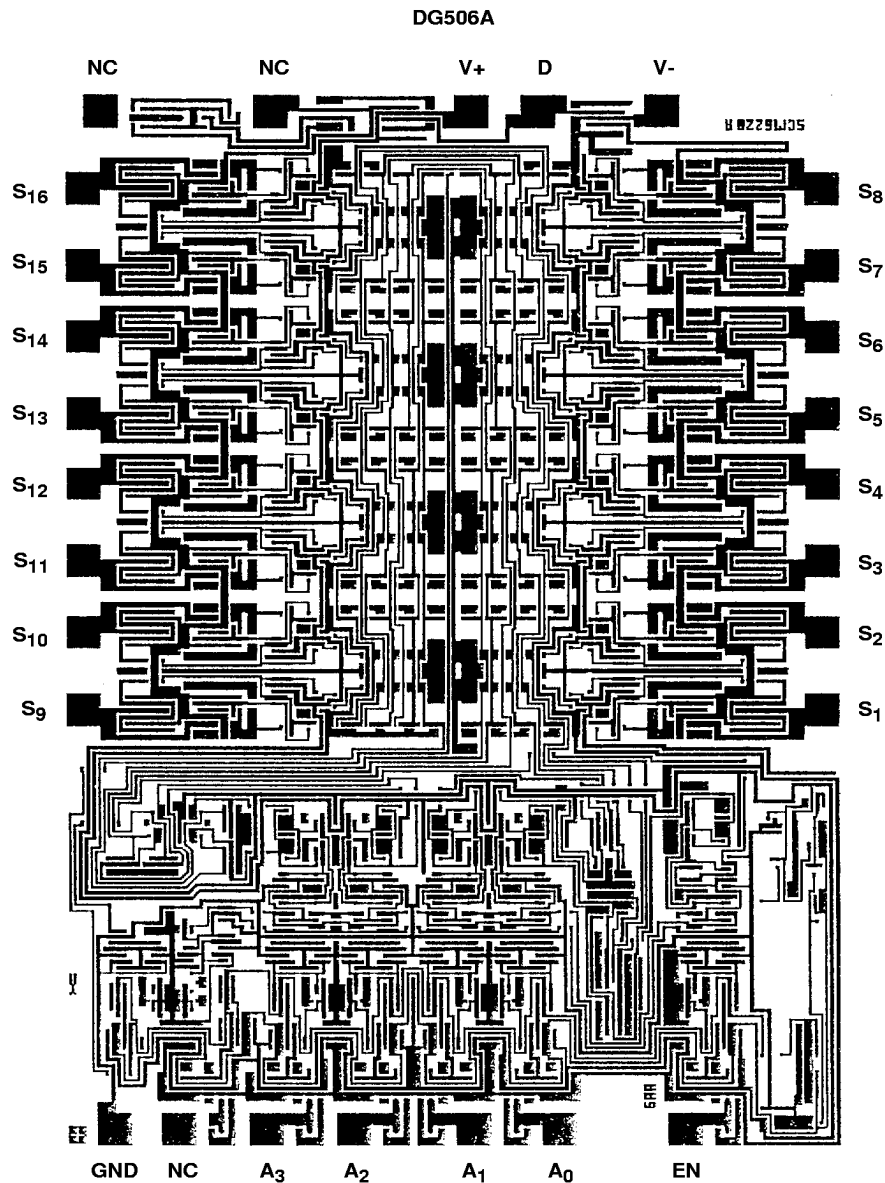
Thickness: PSG: 7k $\text{\AA}$ $\pm$ 1.4k $\text{\AA}$

Nitride: 8k $\text{\AA}$ $\pm$ 1.2k $\text{\AA}$

WORST CASE CURRENT DENSITY:

9.1 x 10⁴ A/cm²

Metallization Mask Layout



Die Characteristics

DIE DIMENSIONS:

3810 μ m x 2770 μ m

METALLIZATION:

Type: Al

Thickness: 10k $\text{\AA}$ $\pm$ 1k $\text{\AA}$

PASSIVATION:

Type: PSG/Nitride

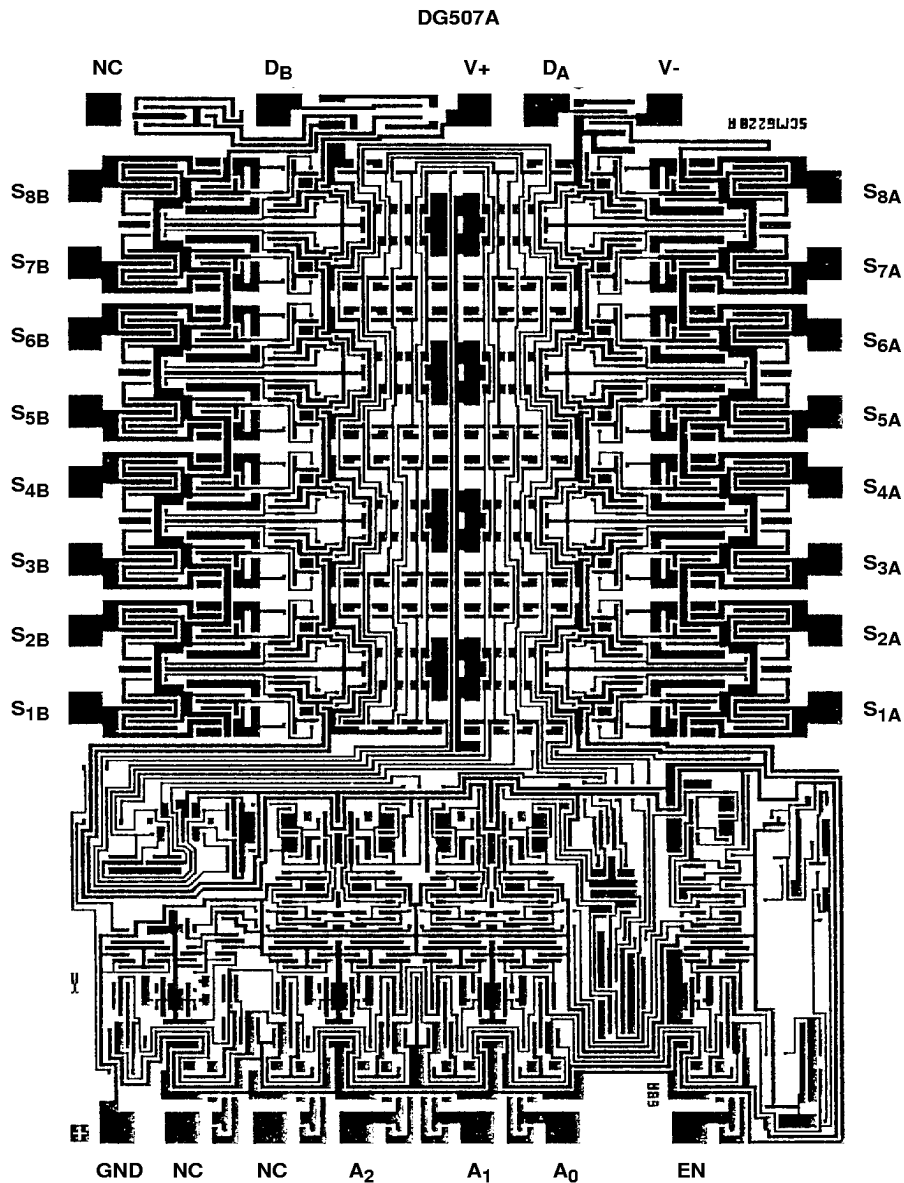
Thickness: PSG: 7k $\text{\AA}$ $\pm$ 1.4k $\text{\AA}$

Nitride: 8k $\text{\AA}$ $\pm$ 1.2k $\text{\AA}$

WORST CASE CURRENT DENSITY:

9.1 x 10⁴ A/cm²

Metallization Mask Layout



Die Characteristics

DIE DIMENSIONS:

3100 μ m x 2083 μ m

METALLIZATION:

Type: Al

Thickness: 10k $\text{\AA}$ $\pm$ 1k $\text{\AA}$

PASSIVATION:

Type: PSG/Nitride

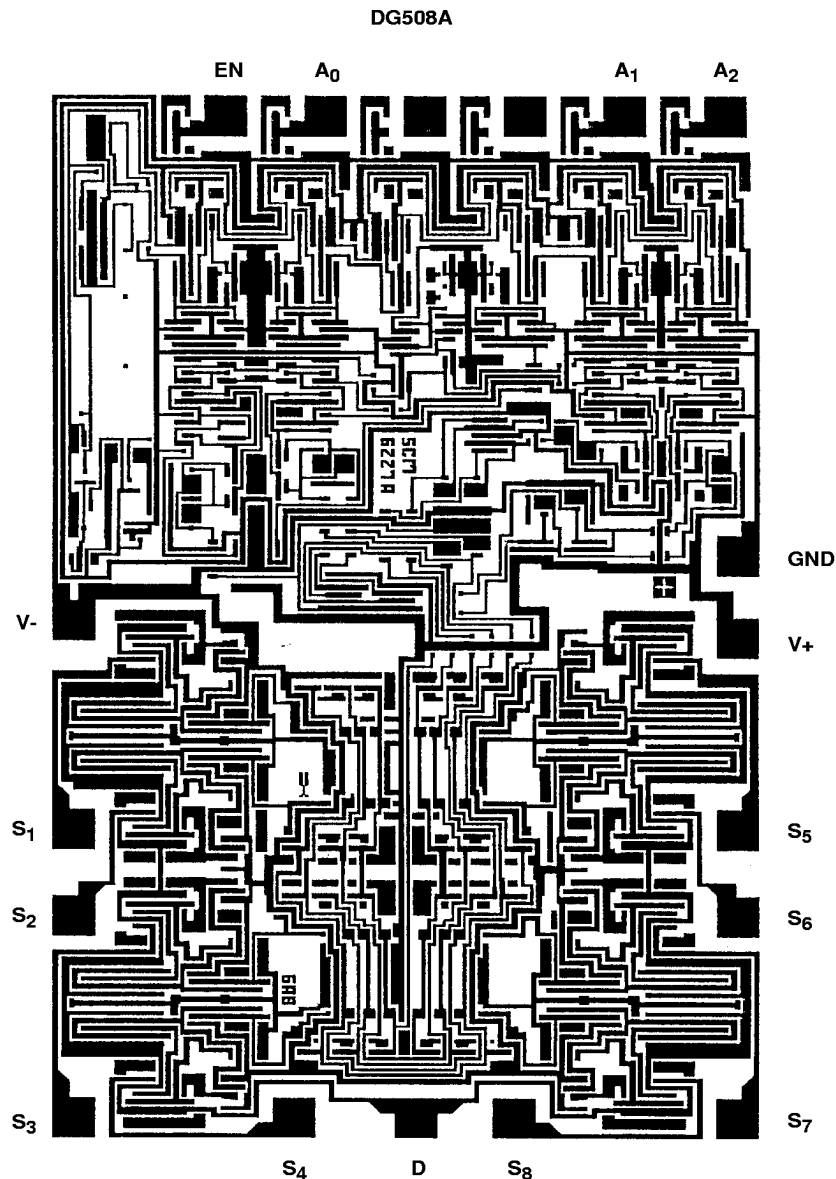
Thickness: PSG: 7k $\text{\AA}$ $\pm$ 1.4k $\text{\AA}$

Nitride: 8k $\text{\AA}$ $\pm$ 1.2k $\text{\AA}$

WORST CASE CURRENT DENSITY:

9.1×10^4 A/cm²

Metallization Mask Layout



Die Characteristics

DIE DIMENSIONS:

3100 μ m x 2083 μ m

METALLIZATION:

Type: Al

Thickness: 10k $\text{\AA}$ $\pm$ 1k $\text{\AA}$

PASSIVATION:

Type: PSG/Nitride

Thickness: PSG: 7k $\text{\AA}$ $\pm$ 1.4k $\text{\AA}$

Nitride: 8k $\text{\AA}$ $\pm$ 1.2k $\text{\AA}$

WORST CASE CURRENT DENSITY:

9.1 x 10⁴ A/cm²

Metallization Mask Layout

